IEEE WIE-CS DELHI SECTION CONGRESS 2015

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IEEE WIE- CS Delhi Section Congress 2015 was held at Netaji Subhash Institute of Technology (NSIT), Dwarka, New Delhi on April 26, 2015. Ankit Saxena, Anjali Kataria, and Himanshi Jhamb presented their project Analysis on Credit Card Fraud Detection. The project the credit card frauds were analyzed and various techniques for detecting the credit card fraud were created using the concept of Genetic Algorithm. The team won the First prize at this project competition.

Anjali Kataria and Ankit Saxena